**SEM - Carl Zeiss Merlin**

*Scanning Electron Microscope - Carl Zeiss Merlin*

- **Description**
  
  The *Merlin* is a high-resolution Field-Emission Scanning Electron Microscope (FE-SEM) designed for high contrast low-voltage imaging of delicate samples with resolution better than one nanometer. The Merlin has several low-noise backscatter and secondary electron detectors, a novel charging compensation mode, and has become our primary tool for studying soft materials samples such as polymers, nanoparticles, and active biological materials such as patterned silicon nanowires.

- **Configuration**
  
  - High-resolution model (40nA)
  - Detectors: In-Lens, EsB, AsB, & SE2
  - 80mm Airlock
  - GIS Charge Compensator (N2)
  - IBSS GC10x Plasma Asher
  - Spiced SC-20DC

- **Training**
  
  Users may request SEM training on the Merlin

- **Location**

  SEM Lab: GCIS ESB28A

- **Contact**

  Qiti Guo